



The Aim of the Conference:

You are cordially invited to attend the International Conference on Quantum Metrology (QM) in Poznan, Poland. The QM'2011 is organized by Poznan University of Technology (Poland) and Friedrich-Schiller University in Jena (Germany).

An aim of the conference is the presentation of results of research and of development, both theoretical and application, in the quantum metrology. In the intention of organizers the QM conference has to be a conference, addressed to metrologists and physicists. We foresee the participation in the conference of guests invited to uttering of short lectures.

The conference language is English. Presentations of reviewed papers will take place on oral plenary sessions, and in the case of the greater number of papers also on a poster session.

Registration fee:

The registration fee will be **250 €**. The deadline for the fee is **March 31, 2011**. The fee will include proceedings, beverages, lunch all 3 days and a conference dinner on May 12th.

The fee **does not include** accomodation.

Conference schedule

February 11, 2011

Deadline for full papers.

March 15, 2011

Notification of papers acceptance.

March 31, 2011

Deadline for payment of the conference fee

May 11 - 13, 2011

International Conference on
Quantum Metrology
Poznan, Poland

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QM'2011

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International Conference on Quantum Metrology

organized by
Poznan University of Technology, Poland
Friedrich-Schiller University, Jena, Germany



Poznan, Poland
May 11th to 13th, 2011



Chairmen of the Conference

Paul Seidel - Co-Chairman

- Friedrich-Schiller University, Jena, Germany

Waldemar Nawrocki - Co-Chairman

- Poznan University of Technology, Poznan, Poland

International Scientific Committee

Paul Seidel - Chairman

- Friedrich-Schiller University, Jena, Germany

Józef Barnaś

- Adam Mickiewicz University, Poznan, Poland

Teodor Gotszalk

- Wrocław University of Technology, Wrocław, Poland

Nicos Guskos

- University Athens, Greece

Ling Hao

- National Physical Laboratory, Teddington, UK

Sergei Kruchinin

- Bogolubov Institute for Theoretical Physics, Kiev, Ukraine

Elżbieta Michniewicz

- Central Office of Measures, Warsaw, Poland

Waldemar Nawrocki

- Poznan University of Technology, Poznan, Poland

Berardo Ruggiero

- Institute of Cybernetics, Naples, Italy

Yuri Shukrinov

- Joint Institute for Nuclear Research, Dubna, Russia

Tadeusz Skubis

- Silesian University of Technology, Gliwice, Poland

Yang Ti-ping

- Hefei University of Technology, China

Yasemin Yildiz Yarur

- Namik Kemal University, Tekirdag, Turkey

Alexander Zorin

- Physikalisch-Technische Bundesanstalt, Braunschweig, Germany

Organizing Committee

Waldemar Nawrocki - Chairman

- Poznan University of Technology (PUT), Poland

Michał Maćkowski - Scientific Secretary

- PUT

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Krzysztof Arnold - PUT

Jakub Pająkowski - PUT

Conference Topics:

- Josephson Effect and Quantum Voltage Standard
- Quantum Hall Effect and Electric Resistance Standard
- Atom Standards of Frequency
- Single Electron Tunneling
- Spintronics
- Scanning Microscopy and Their Applications in Metrology
- Applications of SQUIDS
- Nanometrology
- Measurement Systems for Quantum Metrology
- The Quantum SI - the new system of units
- New Research Areas in Metrology

All current informations of the conference will be accessible on the webpage:

www.kwant.et.put.poznan.pl

Call for papers:

Participants wishing to present a paper are asked to send a full manuscript (up to 6 pages, MS Word 12 pts) in English language (deadline: February 11, 2011). Each manuscript should contain an abstract (200 to 300 words).

Papers will be reviewed by members of the International Scientific Committee and referees. Acceptance of papers for presentation on the conference will be made by March 15, 2011. The organizers will prepare a book of abstracts at the conference.

Accepted papers will be published in the Polish journal **Elektronika**, the issue June 2011 (after an agreement with authors).

Some papers selected by the Scientific Committee can be published in Polish scientific journal **Metrology and Measurement Systems** (the journal is indexed by Thomson Reuters Master Journal List).



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